TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC74HC279AP,TC74HC279AF

Quad S-R Latch

The TC74HC279A is a high speed CMOS QUAD S-R LATCH fabricated with silicon gate C<sup>2</sup>MOS technology.

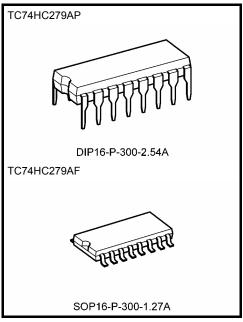
It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

Each latch has an independent Q output and Set and Reset inputs.  $\overline{S}$  and  $\overline{R}$  are active low. When  $\overline{S}$  input is low, the Q output goes high and when  $\overline{R}$  input is low, the Q output goes low. When both  $\overline{S}$  and  $\overline{R}$  are low,  $\overline{S}$  takes precedence resulting Q = low. When both of  $\overline{S}$  and  $\overline{R}$  are held high, Q output doesn't change.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

#### **Features**

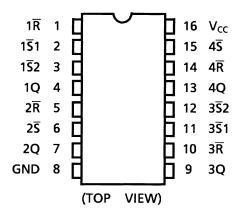
- High speed:  $t_{pd} = 12 \text{ ns (typ.)}$  at  $V_{CC} = 5 \text{ V}$
- Low power dissipation:  $I_{CC} = 2 \mu A \text{ (max)}$  at  $T_{a} = 25 \text{°C}$
- High noise immunity:  $V_{NIH} = V_{NIL} = 28\% V_{CC}$  (min)
- Symmetrical output impedance: | I<sub>OH</sub> | = I<sub>OL</sub> = 4 mA (min)
- Balanced propagation delays:  $t_{pLH} \simeq t_{pHL}$
- Wide operating voltage range: V<sub>CC</sub> (opr) = 2 to 6 V
- Pin and function compatible with 74LS279



Weight

DIP16-P-300-2.54A : 1.00 g (typ.) SOP16-P-300-1.27A : 0.18 g (typ.)

### **Pin Assignment**



2007-10-01

# **IEC Logic Symbol**

$ \begin{array}{c c} 1\overline{S1} & (2) \\ 1\overline{S2} & (3) \\ 1\overline{R} & (1) \end{array} $	& S1	1	( <u>4)</u> 1Q
$ \begin{array}{c c} 1\overline{S2} & (3) \\ 1\overline{R} & (1) \\ 2\overline{S} & (6) \\ 2\overline{R} & (5) \\ 3\overline{S1} & (12) \end{array} $	S2 R	2	(7) 2Q
$ \frac{3S1}{3S2} \frac{(12)}{(10)} $ $ \frac{3S2}{3R} \frac{(15)}{(15)} $ $ \frac{4S}{(14)} $	& S3	3	(9) 3Q
$4\overline{S} + \frac{(15)}{4\overline{R}} + \frac{(14)}{14}$	S4 R	4	(13) 4Q

#### **Truth Table**

Inp	uts	Output
S#	R	Q
Н	Н	Qn
L	Н	Н
Н	L	L
L	L	Н

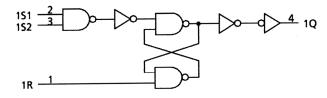
Qn: The level of Q before the indicated input condition were established.

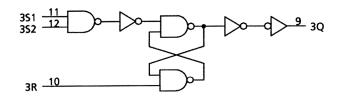
#: For latches with doubles  $\overline{S}$  input.

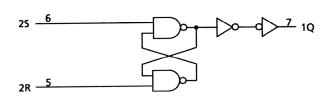
 $H = Both \ \overline{S} \ input high$ 

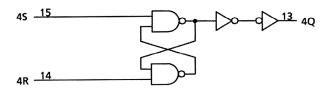
L = One of both inputs low

# **System Diagram**









# <u>TOSHIBA</u>

#### **Absolute Maximum Ratings (Note 1)**

Characteristics	Symbol	Rating	Unit
Supply voltage range	$V_{CC}$	–0.5 to 7	V
DC input voltage	V <sub>IN</sub>	-0.5 to V <sub>CC</sub> + 0.5	V
DC output voltage	V <sub>OUT</sub>	−0.5 to V <sub>CC</sub> + 0.5	V
Input diode current	I <sub>IK</sub>	±20	mA
Output diode current	lok	±20	mA
DC output current	lout	±25	mA
DC V <sub>CC</sub> /ground current	Icc	±50	mA
Power dissipation	PD	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	T <sub>stg</sub>	–65 to 150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of Ta = -40 to  $65^{\circ}C$ . From Ta = 65 to  $85^{\circ}C$  a derating factor of -10 mW/°C shall be applied until 300 mW.

#### **Operating Ranges (Note)**

Characteristics	Symbol	Rating	Unit
Supply voltage	V <sub>CC</sub>	2 to 6	V
Input voltage	V <sub>IN</sub>	0 to V <sub>CC</sub>	V
Output voltage	V <sub>OUT</sub>	0 to V <sub>CC</sub>	٧
Operating temperature	T <sub>opr</sub>	−40 to 85	°C
		0 to 1000 (V <sub>CC</sub> = 2.0 V)	
Input rise and fall time	t <sub>r</sub> , t <sub>f</sub>	0 to 500 (V <sub>CC</sub> = 4.5 V)	ns
		0 to 400 (V <sub>CC</sub> = 6.0 V)	

Note: The operating ranges must be maintained to ensure the normal operation of the device.

Unused inputs must be tied to either VCC or GND.

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### **Electrical Characteristics**

#### **DC Characteristics**

Characteristics	Symbol	Test Condition			-	Га = 25°C			a = o 85°C	Unit
				V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	
				2.0	1.50	_	_	1.50	_	
High-level input voltage	$V_{IH}$	_		4.5	3.15	_	_	3.15	_	V
				6.0	4.20	_	_	4.20	_	
				2.0	_	_	0.50	_	0.50	
Low-level input voltage	$V_{IL}$		_	4.5	_	_	1.35		1.35	V
Ğ				6.0	_	—	1.80	_	1.80	
	V <sub>OH</sub>	VIN = VIH or VIL		2.0	1.9	2.0	_	1.9	_	
			$I_{OH} = -20 \mu A$	4.5	4.4	4.5	_	4.4	_	
High-level output voltage				6.0	5.9	6.0	_	5.9	—	V
			$I_{OH} = -4 \text{ mA}$	4.5	4.18	4.31	_	4.13	_	
			$I_{OH} = -5.2 \text{ mA}$	6.0	5.68	5.80		5.63	_	
		V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>		2.0	_	0.0	0.1	_	0.1	
			$I_{OL} = 20 \mu A$	4.5	_	0.0	0.1	_	0.1	
Low-level output voltage	$V_{OL}$			6.0	_	0.0	0.1	_	0.1	V
			I <sub>OL</sub> = 4 mA	4.5	_	0.17	0.26	_	0.33	
			I <sub>OL</sub> = 5.2 mA	6.0	_	0.18	0.26	_	0.33	
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND		6.0	_	_	±0.1	_	±1.0	μА
Quiescent supply current	Icc	V <sub>IN</sub> = V <sub>CC</sub> or GND		6.0	_	_	2.0	_	20.0	μА

# AC Characteristics (C $_L$ = 15 pF, $V_{CC}$ = 5 V, Ta = 25 $^{\circ}\text{C},$ input: $t_r$ = $t_f$ = 6 ns)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Output transition time	t <sub>TLH</sub>	_	_	4	8	ns
Propagation delay time (\$\overline{S1}\$, \$\overline{S2}\$-Q)	t <sub>pLH</sub>	_	_	12	22	ns
Propagation delay time (\$\overline{S}\$ -Q)	t <sub>pLH</sub>	_	_	9	17	ns
Propagation delay time ( $\overline{R}$ -Q)	t <sub>pLH</sub>	_		11	20	ns



AC Characteristics ( $C_L = 50$  pF, input:  $t_r = t_f = 6$  ns)

Characteristics Symbol		Test Condition		Ta = 25°C			Ta = -40 to 85°C		Unit
			V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	
	t <sub>TLH</sub>		2.0	_	30	75	_	95	
Output transition time	t <sub>THL</sub>	_	4.5 6.0		8 7	15 13	_	19 16	ns
Propagation delay	4		2.0	_	45	130	_	165	
time	t <sub>pLH</sub>	_	4.5	_	15	26	_	33	ns
(\$1, \$\overline{\sigma}2-\overline{Q}\$)	$t_{pHL}$		6.0	_	13	22	_	28	
Propagation delay	<b></b>		2.0	_	38	100	_	125	
time _	t <sub>pLH</sub>	_	4.5	_	12	20	_	25	ns
( <del>S</del> -Q)	t <sub>pHL</sub>		6.0		10	17	_	21	
Propagation delay	$t_pLH$		2.0	_	42	120	_	150	
time _	-	_	4.5	_	14	24	_	30	ns
(R-Q)	t <sub>pHL</sub>		6.0		12	20	_	26	
Input capacitance	C <sub>IN</sub>				5	10		10	pF
Power dissipation capacitance	C <sub>PD</sub> (Note)				18				pF

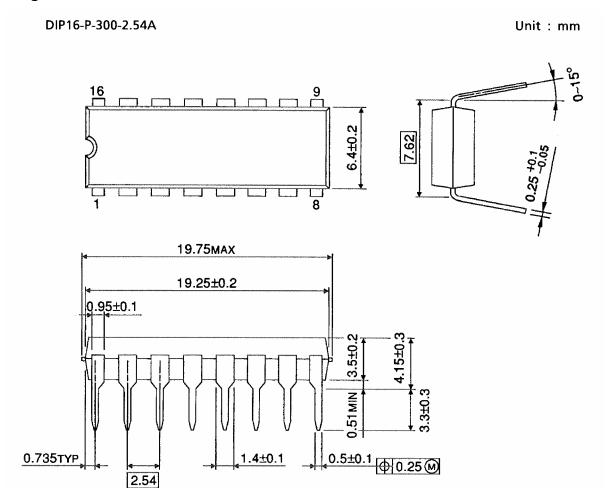
Note: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

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Average operating current can be obtained by the equation:

$$I_{CC}$$
 (opr) =  $C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/4$  (per circuit)

# **Package Dimensions**

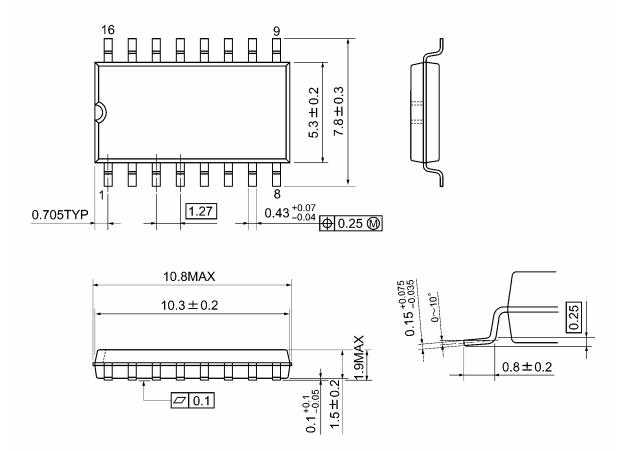


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Weight: 1.00 g (typ.)

# **Package Dimensions**

SOP16-P-300-1.27A Unit: mm



Weight: 0.18 g (typ.)

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20070701-EN GENERAL

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